Application/Control No. Applicant(s)/Patent Under Reexamination 10/627,713 FUJISAWA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2824 Hien N Nguyen **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY US-5,369,619 11-1994 Ohba, Atsushi 365/230.03 Α В US-5,838,627 11-1998 Tomishima et al. 365/230.03 * С US-6,310,815 10-2001 Yamagata et al. 365/230.03 D US-Ε US-US-F US-G US-Н ı US-J US-Κ US-US-US-FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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